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PTO-1449 U.S. DEPARTMENT OF COMMERCE (Rev. 2-32) PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO.	SERIAL NO.
1209-48	10/825,529
APPLICANT Mikhail Boroditsky, et al.	CONFIRMATION NO. 8388
FILING DATE	GROUP
April 15, 2004	2874

U.S. PATENT PUBLICATIONS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
a	2003/156776 A1	Aug. 21, 2003	Han Ki-Ho et al.			
02	2003/175034 A1	Sept. 18, 2003	Noe Reinhid			_
ce	2003/184735 A1	Oct. 2, 2003	Kotten Klaus et al.			

209797_1

EXAMINER CLASSIFICATIONS DATE CONSIDERED 6-20-06

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Rev. 2-32) PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 1209-48	SERIAL NO. Unassigned	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	APPLICANT Mikhail Boroditsky, et al.	CONFIRMATION NO. Unassigned	
(Use several sheets if necessary)	FILING DATE Herewith	GROUP Unassigned	

U.S. PATENT DOCUMENTS

		U.S. FA.	TENT DOCUMENTS			
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<u>c</u> l	5,717,489	2/10/98	Ozeki, et al.	-		
(2	5,930,414	7/27/99	Fishman, et al.			
U	5,995,228	11/30/99	Otani, et al.			
ce	6,380,533	4/30/02	Jopson, et al.			*
e	6,381,385	4/30/02	Watley, et al.			
(l	6,459,830	10/1/02	Pua, et al.			
ce	6,542,650	4/1/03	Khosravani, et al.			
le	6,556,732	4/29/03	Chowdhury, et al.			,
ce	6,647,176	11/11/03	Pua, et al.			

	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
Ce	M. Boroditsky, et al., "In-Service Measurements of Polarization-Mode Dispersion and Correlation to Bit-Error Rate", <i>IEEE Phot. Tech. Lett.</i> , Vol. 15, No. 4, pp. 572-574 (April 2003)
Cl	Normand Cyr, Andre Girard, and Gregory W. Schinn, "Stokes Parameter Analysis Method, the Consolidated Test Method for PMD Measurements", NFOEC '99 Convention (Chicago, Ill. 1999)

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